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Search:  The ACM Digital Library  The Guide

+garbage +"first heap" +"second heap" +transaction +persist

Nothing Found

Your search for +garbage +"first heap" +"second heap" +transaction +persist did not return any results.

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Please review the [Quick Tips](#) below or for more information see the [Search Tips](#).

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**Quick Tips**

- Enter your search terms in lower case with a space between the terms.  
  
sales offices
- You can also enter a full question or concept in plain language.  
  
Where are the sales offices?
- Capitalize proper nouns to search for specific people, places, or products.  
  
John Colter, Netscape Navigator
- Enclose a phrase in double quotes to search for that exact phrase.  
  
"museum of natural history" "museum of modern art"
- Narrow your searches by using a + if a search term must appear on a page.  
  
museum +art
- Exclude pages by using a - if a search term must not appear on a page.  
  
museum -Paris

Combine these techniques to create a specific search query. The better your description of the information you want, the more relevant your results will be.

museum +"natural history" dinosaur -Chicago



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IEEE Xplore Search

Search Results

Results for "((garbage <and> first <phrase> heap <and> second <phrase> heap <and> transa..."

Your search matched 0 of 1164322 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

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**Key**

IEEE JNL IEEE Journal or Magazine

Modify Search

IEEE JNL IEE Journal or Magazine

Check to search only within this results set

IEEE CNF IEEE Conference Proceeding

Display Format:  Citation  Citation & Abstract

IEEE CNF IEE Conference Proceeding

.....

IEEE STD IEEE Standard

.....

No results were found.

Please edit your search criteria and try again. Refer to the Help pages if you need assistance revising your search.

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## Freeform Search

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**Database:**  US Pre-Grant Publication Full-Text Database  
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 EPO Abstracts Database  
 JPO Abstracts Database  
 Derwent World Patents Index  
 IBM Technical Disclosure Bulletins

**Term:**

**Display:**  Documents in Display Format:  Starting with Number

**Generate:**  Hit List  Hit Count  Side by Side  Image

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### Search History

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**DATE:** Sunday, May 29, 2005 [Printable Copy](#) [Create Case](#)

**Set Name** **Query**

side by side

*DB=PGPB,USPT; PLUR=YES; OP=ADJ*

<b><u>Set Name</u></b>	<b><u>Query</u></b>	<b><u>Hit Count</u></b>	<b><u>Set Name</u></b>
<u>L6</u>	L5 and gap	1	<u>L6</u>
<u>L5</u>	L4 and contiguous	5	<u>L5</u>
<u>L4</u>	L3 and persist\$3	5	<u>L4</u>
<u>L3</u>	L2 and (first near3 heap same second near3 heap)	14	<u>L3</u>
<u>L2</u>	L1 and (garbage near3 collect\$3)	343	<u>L2</u>
<u>L1</u>	707/206.ccls.	529	<u>L1</u>

END OF SEARCH HISTORY